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Table of Contents

Foreword	iv
Organizing Committee	v
Steering Committee	vi
Program Committee	vii
Tutorials	ix
Keynotes	xii
Call For Papers of ITC-Asia 2018	xvi

Session B1: Analog/Mixed Signal Test

Low-Distortion Signal Generation for Analog/Mixed-Signal Circuit Testing with Digital ATE	2
<i>Masayuki Kawabata, Koji Asami, Shohei Shibuya, Tomonori Yanagida, and Haruo Kobayashi</i>	
A Quick Jitter Tolerance Estimation Technique for Bang-bang CDRs.....	8
<i>Yen-Long Lee and Soon-Jyh Chang</i>	
Evaluation of Loop Transfer Function Based Dynamic Testing of LDOs.....	14
<i>Mehmet Ince, Ender Yilmaz, Jae Woong Jeong, Leroy Winemberg, and Sule Ozev,</i>	

Session C1: Cell-Aware Test

Test Generation for Open and Delay Faults in CMOS Circuits	21
<i>Cheng-Hung Wu, Kuen-Jong Lee, and Sudhakar M. Reddy</i>	
Cell-Aware Test Generation Time Reduction by Using Switch-Level ATPG.....	27
<i>Po-Yao Chuang, Cheng-Wen Wu, and Harry H. Chen</i>	

Session B2: Detection, Diagnosis, Debug

GPU Accelerated Fault Dictionary Generation for the TRAX Fault Model	34
<i>Matthew Beckler and R. D. (Shawn) Blanton</i>	
Physical-aware Diagnosis of Multiple Interconnect Defects	40
<i>Po-Hao Chen, Chi-Lin Lee, Jing-Yu Chen, Po-Wei Chen, and James Chien-Mo Li</i>	

A Run-Pause-Resume Silicon Debug Technique for Multiple Clock Domain Systems	46
<i>Shuo-Lian Hong and Kuen-Jong Lee</i>	
A Hybrid Concurrent Error Detection Scheme for Simultaneous Improvement on Probability of Detection and Diagnosability	52
<i>Chih-Hao Wang and Tong-Yu Hsieh</i>	

Session C2: Test for IoT and Automotives

A Dependable AMR Sensor System for Automotive Applications	59
<i>Andreina Zambrano, Hans G. Kerkhoff</i>	
An Automotive MP-SoC Featuring an Advanced Embedded Instrument Infrastructure for High Dependability	65
<i>Hans G. Kerkhoff, Ghazanfar Ali, Hassan Ebrahimi, and Ahmed Ibrahim</i>	
Symbiotic System Models for Efficient IOT System Design and Test	71
<i>Cheng-Wen Wu, Bing-Yang Lin, Hsin-Wei Hung, Shu-Mei Tseng, and Chi Chen</i>	
A Lightweight X-Masking Scheme for IoT Designs	77
<i>Daniel Tille, Benedikt Gottinger, Ulrike Pfannkuchen</i>	

Session B3: Test for InFO and SoC

Fan-Out Wafer Level Chip Scale Package Testing	84
<i>Hao Chen, Hung-Chih Lin, and Min-Jer Wang</i>	
Testing-for-Manufacturing (TFM) for Ultra-thin IPD on InFO.....	90
<i>Tang-Jung Chiu, Yu-Lun Tseng, Yen-Cheng Lin, Yi-Chen Wang, Hung-Chih Lin, and Min-Jer Wang</i>	
Test Strategy for Storage SOCs	96
<i>Abhishek Bhattacharya and Ramesh Tekumalla</i>	

Session C3: Memory Test

Adaptive Block-Based Refresh Techniques for Mitigation of Data Retention Faults and Reduction of Refresh Power.....	101
<i>Shyue-Kung Lu and Hung-Kai Huang</i>	
Software-Hardware-Cooperated Built-In Self-Test Scheme for Channel-Based DRAMs	107
<i>Tsung-Fu Hsieh, Jin-Fu Li, Kuan-Te Wu, Jenn-Shiang Lai, Chih-Yen Lo, Ding-Ming Kwai, and Yung-Fa Chou</i>	
Adapting an Industrial Memory BIST solution for testing CAMs	112
<i>Jais Abraham, Uttam Garg, Glenn Colon-Bonet, Ramesh Sharma, Chennian Di, Benoit Nadeau-Dostie, Etienne Racine, and Martin Keim</i>	

Session B4: On-Chip Test Infrastructure

Trustworthy Reconfigurable Access to On-Chip Infrastructure	119
<i>Michael A. Kochte, Rafal Baranowski, and Hans-Joachim Wunderlich</i>	
On the effects of real time and contiguous measurement with a digital temperature and voltage sensor	125
<i>Yousuke Miyake, Yasuo Sato, and Seiji Kajihara</i>	
Enhancing Security of Logic Encryption Using Embedded Key Generation Unit.....	131
<i>Rajit Karmakarx, Santanu Chattopadhyayx, and Rohit Kapur</i>	

Session C4: Advanced Test Practices

A Mathematical Model to assess the influence of parallelism in a Semiconductor Back-End Test Floor	138
<i>Davide Appello, Mariapina Laurino, and Marco Pranzo</i>	
A Fully Automatic Test System for Characterizing Large-Array Fine-Pitch Micro-Bump Probe Cards	144
<i>Erik Jan Marinissen, Ferenc Fodor, Bart De Wachter, Joerg Kiesewetter, Eric Hill, and Ken Smith</i>	
Test Item Priority Estimation for High Parallel Test Efficiency under ATE Debug Time Constraints	150
<i>Young-woo Lee, Inhyuk Choi, Kang-Hoon Oh, James Jinsoo Ko, and Sungho Kang</i>	

Session B5: Verification and Fault Tolerance

State Assignment for Fault Tolerant Stochastic Computing with Linear Finite State Machines.....	156
<i>Hideyuki Ichihara, Motoi Fukuda, Tsuyoshi Iwagaki, and Tomoo Inoue</i>	
An Integrated Design Environment of Fault Tolerant Processors with Flexible HW/SW Solutions for Versatile Performance/Cost/Coverage Tradeoffs	162
<i>Yi-Ju Ke, Yi-Chieh Chen, and Ing-Jer Huang</i>	
Speeding Up Power Verification by Merging Equivalent Power Domains in RTL Design with UPF	168
<i>Charles C.-H. Hsu and Charles H.-P. Wen</i>	

Author Index.....	174
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